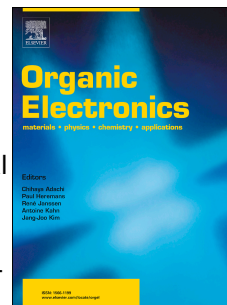


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Enhanced performance and reliability of organic thin film transistors through structural scaling in gravure printing process

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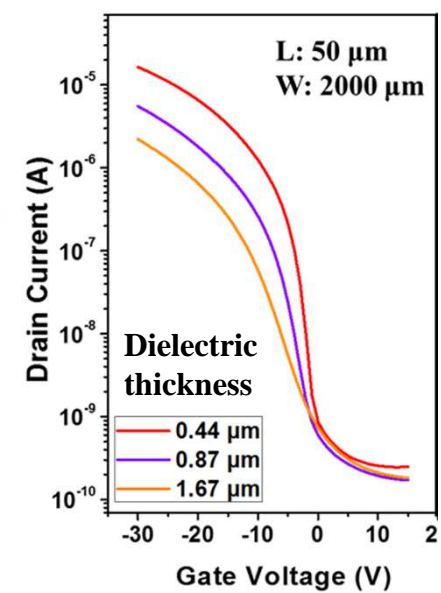
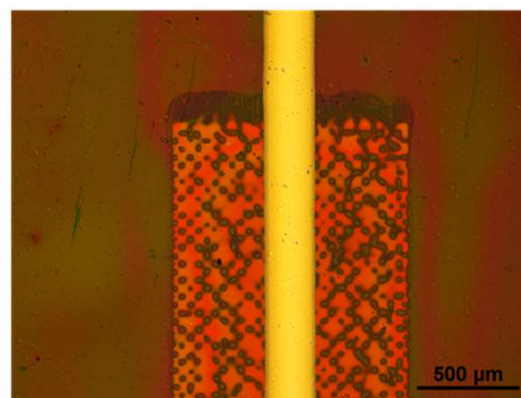
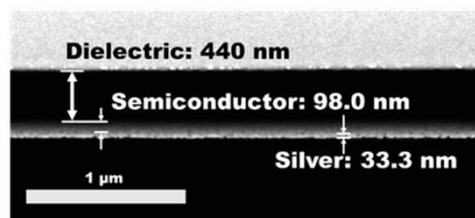
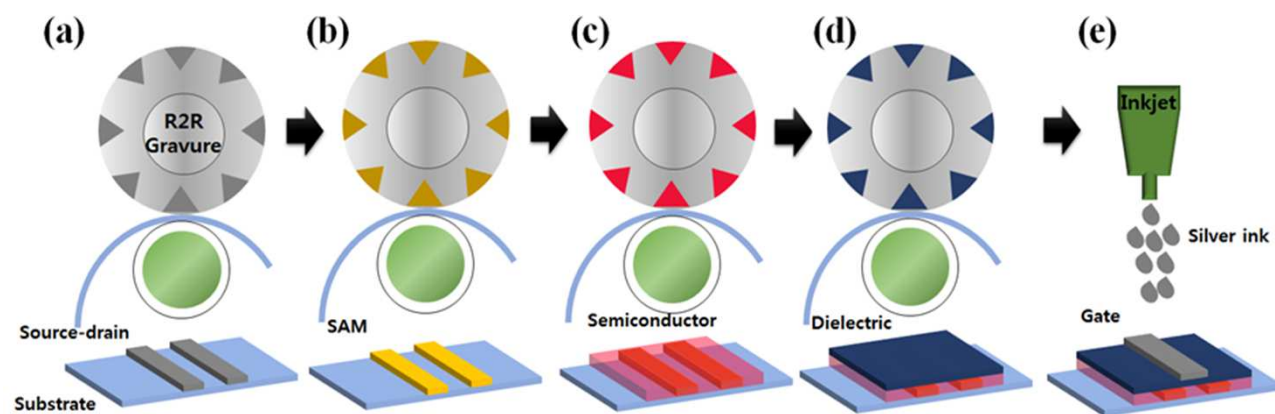
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